

R1LP5256E Series

256Kb Advanced LPSRAM (32k word x 8bit)

R10DS0070EJ0100 Rev.1.00 2011.04.13

Description

The R1LP5256E Series is a family of low voltage 256-Kbit static RAMs organized as 32,768-word by 8-bit, fabricated by Renesas's high-performance 0.15um CMOS and TFT technologies. The R1LP5256E Series has realized higher density, higher performance and low power consumption. The R1LP5256E Series is suitable for memory applications where a simple interfacing, battery operating and battery backup are the important design objectives. It has been packaged in 28-pin SOP and 28-pin TSOP.

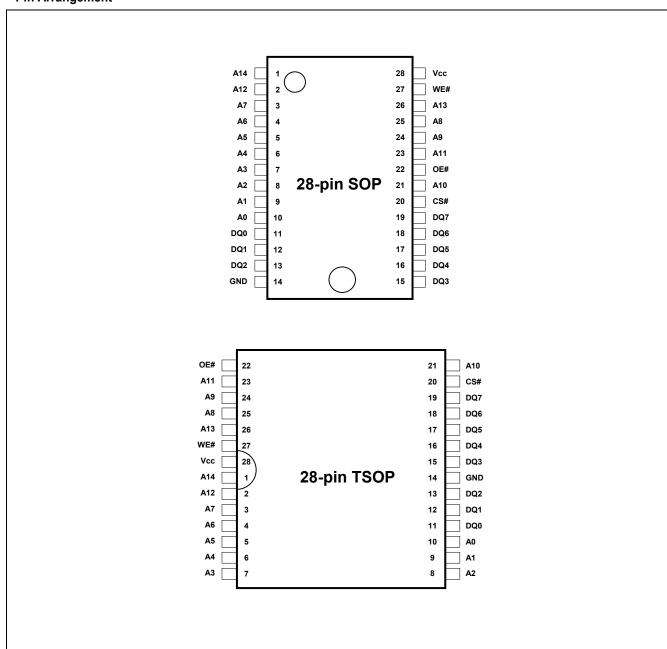
Features

- Single 4.5V~5.5V power supply
- Small stand-by current: 1µA (5.0V, typical)
- No clocks, No refresh
- All inputs and outputs are TTL compatible.
- Easy memory expansion by CS#
- Common Data I/O
- Three-state outputs: OR-tie Capability
- OE# prevents data contention on the I/O bus

Ordering Information

| Orderable Part Name | Access time | Temperature Range | Package | Shipping Container | Quantity | |
|---------------------|-------------|----------------------|-----------------------------------|-----------------------|---|--|
| R1LP5256ESP-5SR#B0 | 55 ns | 0 ~ +70°C | | | | |
| R1LP5256ESP-5SI#B0 | 22 118 | -40 ~ +85°C | | Tube | Max. 30pcs/Tube | |
| R1LP5256ESP-7SR#B0 | 70 ns | 0 ~ +70°C | 450-mil 28-pin | rube | Max. 300pcs/Inner Bag Max. 1200pcs/Inner Box | |
| R1LP5256ESP-7SI#B0 | 70 118 | -40 ~ +85°C | plastic SOP | | · | |
| R1LP5256ESP-5SR#S0 | 55 ns | 0 ~ +70°C | PRSP0028DB-B | | | |
| R1LP5256ESP-5SI#S0 | 55 118 | -40 ~ +85°C | (28P2W-C) | Embossed | 1000pcs/Reel | |
| R1LP5256ESP-7SR#S0 | 70 ns | 0 ~ +70°C | | tape | 1000pcs/Neel | |
| R1LP5256ESP-7SI#S0 | 70115 | -40 ~ +85°C | | | | |
| R1LP5256ESA-5SR#B0 | 55 ns | 0 ~ +70°C | | | | |
| R1LP5256ESA-5SI#B0 | 55 118 | -40 ~ +85°C | | Tray | Max. 234pcs/Tray | |
| R1LP5256ESA-7SR#B0 | 70 ns | 0 ~ +70°C | 8mm×13.4mm 28-pin plastic TSOP | ITay | Max. 1872pcs/Inner Box | |
| R1LP5256ESA-7SI#B0 | 70115 | -40 ~ +85°C | (normal-bend type) | | | |
| R1LP5256ESA-5SR#S0 | 55 ns | 0 ~ +70°C | DT0400074.4 | | | |
| R1LP5256ESA-5SI#S0 | 55 118 | -40 ~ +85°C | PTSA0028ZA-A (28P2C-A) | Embossed | 1000pcs/Reel | |
| R1LP5256ESA-7SR#S0 | 70 ns | 0 ~ +70°C | (==: 20 7.) | tape | 1000pcs/Reel | |
| R1LP5256ESA-7SI#S0 | 10115 | -40 ~ +85°C | | | | |

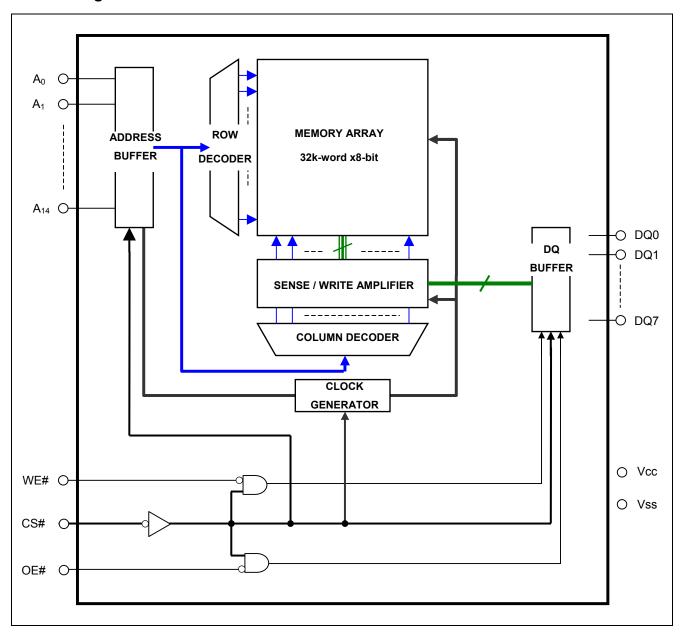
Pin Arrangement



Pin Description

| Pin name | Function |
|------------|-------------------|
| Vcc | Power supply |
| Vss | Ground |
| A0 to A14 | Address input |
| DQ0 to DQ7 | Data input/output |
| CS# | Chip select |
| WE# | Write enable |
| OE# | Output enable |

Block Diagram



Operation Table

| CS# | WE# | OE# | DQ0~7 | Operation |
|-----|-----|-----|--------|----------------|
| Н | Х | Х | High-Z | Stand-by |
| L | L | Х | Din | Write |
| L | Н | L | Dout | Read |
| L | Н | Н | High-Z | Output disable |

Note 1. H: V_{IH} L:V_{IL} X: V_{IH} or V_{IL}

Absolute Maximum

| Parameter | Symbol | Symbol Value | | unit |
|---|----------------|-------------------------|-----------------------|------|
| Power supply voltage relative to Vss | Vcc | -0.3 | to +7 | V |
| Terminal voltage on any pin relative to Vss | V _T | -0.3 ^{*1} to ' | Vcc+0.3 ^{*2} | V |
| Power dissipation | P _T | 0.7 | | W |
| Operation temperature | Topr*3 | R Ver. | 0 to +70 | °C |
| Operation temperature | ТОРГ | I Ver. | -40 to +85 | |
| Storage temperature range | Tstg | -65 to | -65 to 150 | |
| Storage temperature range under hige | Tbias*3 | R Ver. | 0 to +70 | °C |
| Storage temperature range under bias | ibids | I Ver. | -40 to +85 | |

Note 1. –3.0V for pulse ≤ 30ns (full width at half maximum)

- 2. Maximum voltage is +7V.
- 3. Ambient temperature range depends on R/I-version. Please see table on page 1.

DC Operating Conditions

| Parameter | | Symbol | Min. | Тур. | Max. | Unit | Note |
|---------------------------|----------------|-----------------|------|------|---------|------|------|
| Supply voltage | Supply voltage | | 4.5 | 5.0 | 5.5 | V | |
| | | Vss | 0 | 0 | 0 | V | |
| Input high voltage | | V _{IH} | 2.2 | - | Vcc+0.3 | V | |
| Input low voltage | | V_{IL} | -0.3 | - | 0.8 | V | 1 |
| Ambient temperature range | R Ver. | Та | 0 | - | +70 | °C | 2 |
| Ambient temperature range | I Ver. | Id | -40 | - | +85 | °C | 2 |

Note 1. -3.0V for pulse ≤ 30 ns (full width at half maximum)

DC Characteristics

| Parameter | Symbol | Min. | Тур. | Max. | Unit | Test conditions | | |
|---------------------------|------------------|--------------|-----------------|------|------|---|---|--|
| Input leakage current | | - | - | 1 | μΑ | Vin = Vss to Vcc | | |
| Output leakage current | I _{LO} | - | - | 1 | μА | CS# =V _{IH} C | or OE# =V _{IH} , to Vcc | |
| Average operating current | I _{CC1} | - | 25 | 35 | mA | | duty =100%, II/O = 0mA Others = V_{IH}/V_{IL} | |
| | I _{CC2} | - | 2 | 4 | mA | CS# ≤ 0.2\ | s, duty =100%, II/O = 0mA /, I.2V, V _{IL} ≤ 0.2V | |
| Standby current | I _{SB} | - | - | 3 | mA | CS# =V _{IH} , Others = Vss to Vcc | | |
| Standby current | | - | 1 ^{*1} | 2 | μΑ | ~+25°C | Vin = Vss to Vcc | |
| | los | - | - | 3 | μА | ~+40°C | CS#≥ Vcc-0.2V | |
| | I _{SB1} | - | - | 8 | μΑ | ~+70°C | | |
| | | - | - | 10 | μА | ~+85°C | | |
| Output high voltage | V _{OH} | 2.4 | - | - | V | I _{OH} = -1mA | | |
| | V _{OH2} | Vcc - 0.5 | - | - | V | I _{OH} = -0.1m | nA | |
| Output low voltage | V _{OL} | - | - | 0.4 | V | I _{OL} = 2mA | | |

Note 1. Typical parameter indicates the value for the center of distribution at 5.0V (Ta= 25°C), and not 100% tested.

^{2.} Ambient temperature range depends on R/I-version. Please see table on page 1.

Capacitance

$$(Vcc = 4.5V \sim 5.5V, f = 1MHz, Ta = 0 \sim +70^{\circ}C / -40 \sim +85^{\circ}C^{*2})$$

| Parameter | Symbol | Min. | Тур. | Max. | Unit | Test conditions | Note |
|----------------------------|------------------|------|------|------|------|-----------------|------|
| Input capacitance | C in | - | - | 6 | pF | Vin =0V | 1 |
| Input / output capacitance | C _{I/O} | - | - | 8 | pF | VI/O =0V | 1 |

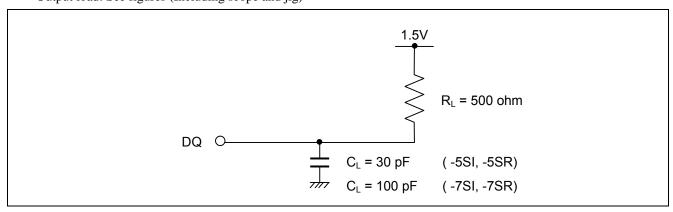
Note 1. This parameter is sampled and not 100% tested.

2. Ambient temperature range depends on R/I-version. Please see table on page 1.

AC Characteristics

Test Conditions (Vcc = $4.5V \sim 5.5V$, Ta = $0 \sim +70^{\circ}C / -40 \sim +85^{\circ}C^{*1}$)

- Input pulse levels: VIL = 0.6V, VIH = 2.4V
- Input rise and fall time: 5ns
- Input and output timing reference level: 1.5V
- Output load: See figures (Including scope and jig)



Note 1. Ambient temperature range depends on R/I-version. Please see table on page 1.

Read Cycle

| Parameter | Symbol | R1LP5256E**-5S* | | R1LP525 | 6E**-7S* | Unit | Note |
|------------------------------------|------------------|-----------------|------|---------|----------|-------|-------|
| Faiailletei | Symbol | Min. | Max. | Min. | Max. | Offic | Note |
| Read cycle time | t _{RC} | 55 | - | 70 | - | ns | |
| Address access time | t _{AA} | - | 55 | - | 70 | ns | |
| Chip select access time | t _{ACS} | - | 55 | - | 70 | ns | |
| Output enable to output valid | toE | - | 30 | - | 35 | ns | |
| Output hold from address change | tон | 10 | - | 10 | - | ns | |
| Chip select to output in low-Z | t _{CLZ} | 5 | - | 5 | - | ns | 2,3 |
| Output enable to output in low-Z | tolz | 5 | - | 5 | - | ns | 2,3 |
| Chip deselect to output in high-Z | t _{CHZ} | 0 | 20 | 0 | 25 | ns | 1,2,3 |
| Output disable to output in high-Z | t _{OHZ} | 0 | 20 | 0 | 25 | ns | 1,2,3 |

Write Cycle

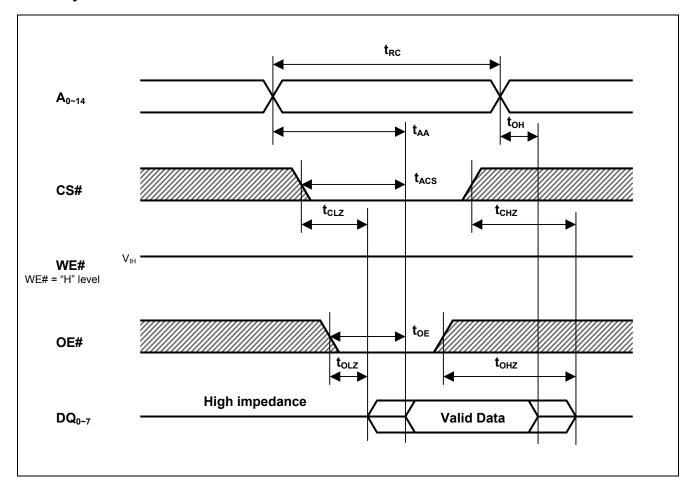
| Parameter | Symbol | Symbol R1LP5256E**-5S* | | R1LP525 | 56E**-7S* | Unit | Note |
|---|------------------|------------------------|------|---------|-----------|-------|------|
| Faranietei | Syllibol | Min. | Max. | Min. | Max. | Offic | Note |
| Write cycle time | twc | 55 | - | 70 | - | ns | |
| Address valid to end of write | t _{AW} | 50 | - | 65 | - | ns | |
| Chip select to end of write | t _{CW} | 50 | - | 65 | - | ns | 5 |
| Write pulse width | t _{WP} | 40 | - | 50 | - | ns | 4 |
| Address setup time | t _{AS} | 0 | - | 0 | - | ns | 6 |
| Write recovery time | t _{WR} | 0 | - | 0 | - | ns | 7 |
| Data to write time overlap | t _{DW} | 25 | - | 30 | - | ns | |
| Data hold from write time | t _{DH} | 0 | - | 0 | - | ns | |
| Output enable from end of write | tow | 5 | - | 5 | - | ns | 2 |
| Output disable to output in high-Z t _{OHZ} | | 0 | 20 | 0 | 25 | ns | 1,2 |
| Write to output in high-Z | t _{WHZ} | 0 | 20 | 0 | 25 | ns | 1,2 |

Note

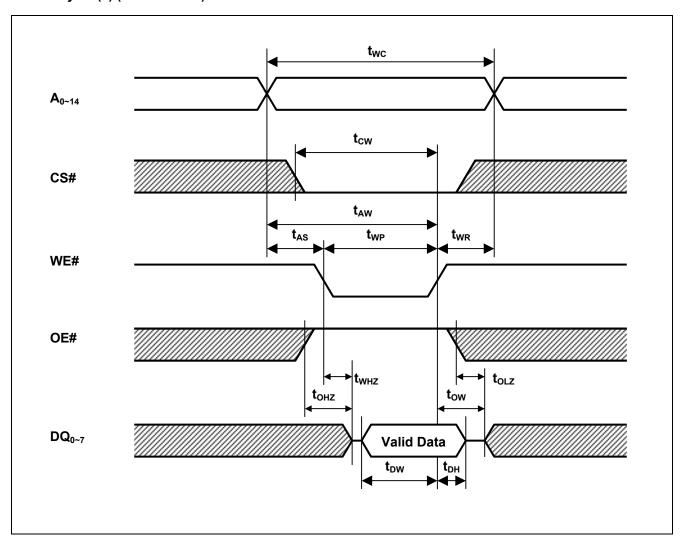
- 1. t_{CHZ}, t_{OHZ} and t_{WHZ} are defined as the time at which the outputs achieve the open circuit conditions and are not referred to output voltage levels.
- 2. This parameter is sampled and not 100% tested.
- 3. At any given temperature and voltage condition, t_{HZ} max is less than t_{LZ} min both for a given device and from device to device.
- 4. A write occurs during the overlap of a low CS#, a low WE#.
 - A write begins at the latest transition among CS# going low and WE# going low.
 - A write ends at the earliest transition among CS# going high and WE# going high.
 - t_{WP} is measured from the beginning of write to the end of write.
- 5. t_{CW} is measured from the later of CS# going low to end of write.
- 6. t_{AS} is measured the address valid to the beginning of write.
- 7. t_{WR} is measured from the earliest of CS# or WE# going high to the end of write cycle.
- 8. Don't apply inverted phase signal externally when DQ pin is output mode.

Timing Waveforms

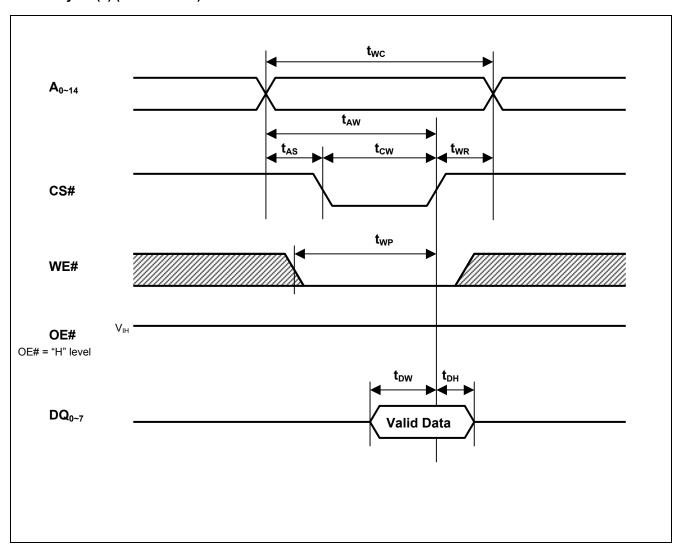
Read Cycle



Write Cycle (1) (WE# CLOCK)



Write Cycle (2) (CS# CLOCK)



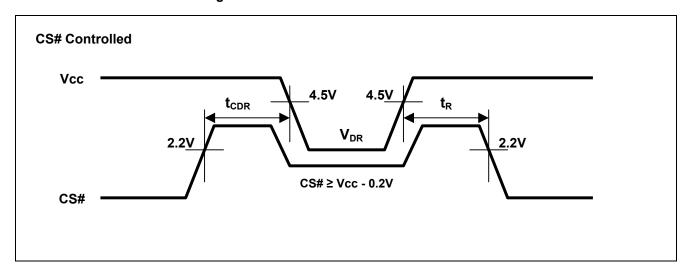
Low Vcc Data Retention Characteristics

| Parameter | Symbol | Min. | Тур. | Max. | Unit | | Test conditions*2 |
|--------------------------------------|------------------|------|-----------------|------|------|-------------------------|---------------------------------------|
| V _{CC} for data retention | V_{DR} | 2.0 | ı | 5.5 | V | Vin ≥ 0V CS# ≥ Vcc | c-0.2V |
| | Iccdr | ı | 1 ^{*1} | 2 | μА | ~+25°C | |
| | | 1 | ı | 3 | μА | ~+40°C | Vcc=3.0V, Vin ≥ 0V, CS# ≥ Vcc-0.2V |
| Data retention current | | 1 | ı | 8 | μА | ~+70°C | C3# 2 VCC-0.2V |
| | | - | - | 10 | μА | ~+85°C | |
| Chip deselect to data retention time | t _{CDR} | 0 | - | - | ns | See reten | tion waveform |
| Operation recovery time | t _R | 5 | - | - | ms | See retention waveform. | |

Note 1. Typical parameter indicates the value for the center of distribution at 3.0V (Ta= 25°C), and not 100% tested.

^{2.} CS# controls address buffer, WE# buffer, OE# buffer and Din buffer. If CS# controls data retention mode, Vin levels (address, WE#, OE#, DQ) can be in the high impedance state.

Low Vcc Data Retention Timing Waveforms



| Revision History R1LP5256E Series Data Sheet |
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| | | Description | | | | |
|------|------------|-------------|----------------------|--|--|--|
| Rev. | Date | Page | Summary | | | |
| 1.00 | 2011.04.13 | - | First Edition issued | | | |
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